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July 2016



FDD10AN06A0

N-Channel PowerTrench[®] MOSFET

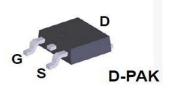
60V, 50A, 10.5m Ω

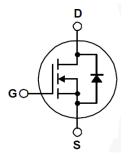
Features

- $R_{DS(on)} = 9.4 \text{ m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V}, I_D = 50 \text{ A}$
- Q_{G(tot)} = 28 nC (Typ.) @ V_{GS} = 10 V
- Low Miller Charge
- Low Q_{rr} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)

Applications

- Consumer Applications
- LED TV
- Synchronous Rectification





General Description

efficiency.

This N-Channel MOSFET has been designed

specifically to improve the overall efficiency of DC/DC

converters using either synchronous or conventional

switching PWM controllers. These MOSFETs feature faster switching and lower gate charge than other

MOSFETs with comparable RDS(ON) specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power

supply designs with higher reliability and system

MOSFEI Maximum Hatings T_C = 25°C unless otherwise noted

Symbol	Parameter	Rating	Unit
V _{DSS}	Drain to Source Voltage	60	V
V _{GS}	Gate to Source Voltage	±20	V
	Drain Current		
۱ _D	Continuous (T_C < 115°C, V_{GS} = 10V)	50	А
	Continuous (T_{amb} = 25°C, V_{GS} = 10V, with $R_{\theta JA}$ = 52°C/W)	11	A
	Pulsed	Figure 4	A
E _{AS}	Single Pulse Avalanche Energy (Note 1)	429	mJ
р	Power dissipation	135	W
PD	Derate above 25°C	0.9	W/ ^o C
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C

Thermal Characteristics

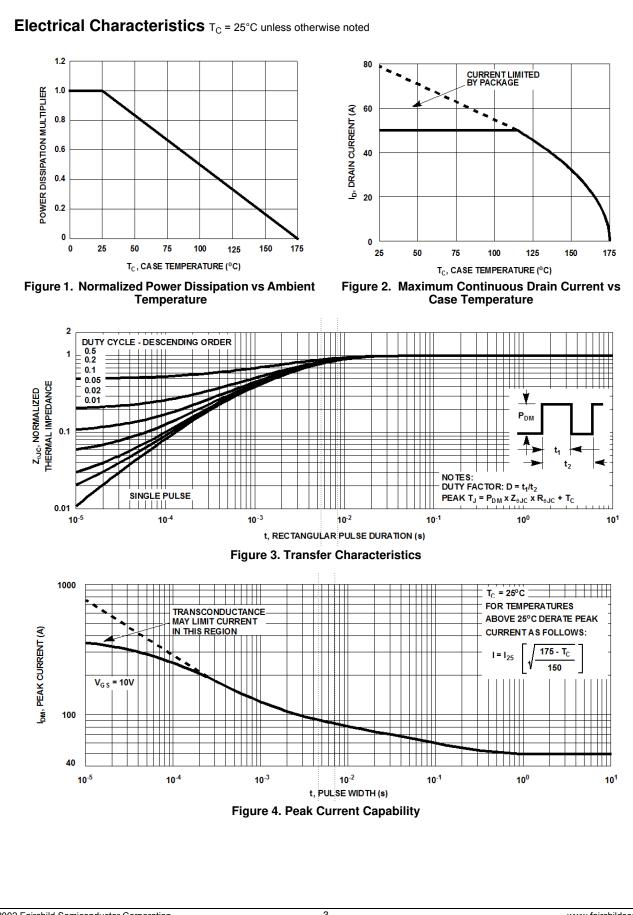
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	1.11	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction to Ambient, Max.	100	°C/W
R _{θJA}	Thermal Resistance Junction to Ambient, 1in ² copper pad area, Max.	52	°C/W

Device Marking FDD10AN06A0		Device	Package	Reel Size	Tape Wi	dth	Quantity	
		FDD10AN06A0	D-PAK	330mm	16mm	16mm		2500 units
Electrica	l Charac	cteristics T _C = 25°C ur	nless otherwise not	ed				
Symbol		Parameter	Test	Conditions	Min	Тур	Max	Unit
Off Charac	teristics				Į	ļ	LI	
B _{VDSS}	Drain to So	ource Breakdown Voltage	I _D = 250μA, V _{GS} = 0V		60	-	-	V
- 0033	Zero Gate Voltage Drain Current Gate to Source Leakage Current			V _{DS} = 50V		-	1	
I _{DSS}			V _{GS} = 0V	$T_{\rm C} = 150^{\circ}{\rm C}$; -	-	250	μA
I _{GSS}			V _{GS} = ±20V			-	±100	nA
On Charac						I	1 1	
V _{GS(TH)}	Gate to Sc	ource Threshold Voltage	V _{GS} = V _{DS} , I _D	V _{GS} = V _{DS} , I _D = 250μA		-	4	V
			I _D = 50A, V _{GS}	I _D = 50A, V _{GS} = 10V		0.0094	0.0105	
-	Drain to S	ouroo On Docistance	I _D = 25A, V _{GS}	$I_{\rm D} = 25$ A, $V_{\rm GS} = 6$ V			0.027	
r _{DS(ON)}	Drain to Source On Resistance		I _D = 50A, V _{GS} T _J = 175 ^o C	I _D = 50A, V _{GS} = 10V,			0.023	Ω
Dynamic C	Character	istics	-				1 1	
C _{ISS}	Input Capa	acitance					-	pF
C _{OSS}	Output Ca	pacitance		$V_{DS} = 25V, V_{GS} = 0V,$ f = 1MHz		340	-	pF
C _{RSS}	Reverse T	ransfer Capacitance				110	-	pF
Q _{g(TOT)}	Total Gate	Charge at 10V	V _{GS} = 0V to 1	0V		28	37	nC
Q _{g(TH)}	Threshold	Gate Charge	V _{GS} = 0V to 2	V V _{DD} = 30V	-	3.5	4.6	nC
Q _{gs}	Gate to Sc	ource Gate Charge		I _D = 50A	-	9.8	-	nC
Q _{gs2}	Gate Char	ge Threshold to Plateau		I _g = 1.0mA		6.4	-	nC
Q _{gd}	Gate to Dr	ain "Miller" Charge				7.8	-	nC
Switching	Characte	eristics (V _{GS} = 10V)						
t _{ON}	Turn-On T	ime			-	-	131	ns
t _{d(ON)}	Turn-On D	elay Time		V _{DD} = 30V, I _D = 50A		8	-	ns
t _r	Rise Time		V _{DD} = 30V, I _D			79	-	ns
t _{d(OFF)}	Turn-Off D	elay Time	V _{GS} = 10V, R	V_{GS}° = 10V, R_{GS} = 10 Ω			-	ns
t _f	Fall Time						-	ns
t _{OFF}	Turn-Off T	ime			-	-	97	ns
Drain-Sou	rce Diode	e Characteristics						
V _{SD}	Source to Drain Diode Voltage		I _{SD} = 50A		-	-	1.25	V
			I _{SD} = 25A	-	-	1.0	V	
t _{rr}	Reverse R	ecovery Time	I _{SD} = 50A, dI _S	-	36	72	ns	
Q _{RR}	Reverse R	ecovered Charge	I _{SD} = 50A, dI _S	-	-	23	nC	

Notes:

1. Starting T_J = 25°C, L = 8.58mH, I_{AS} = 10A.

FDD10AN06A0



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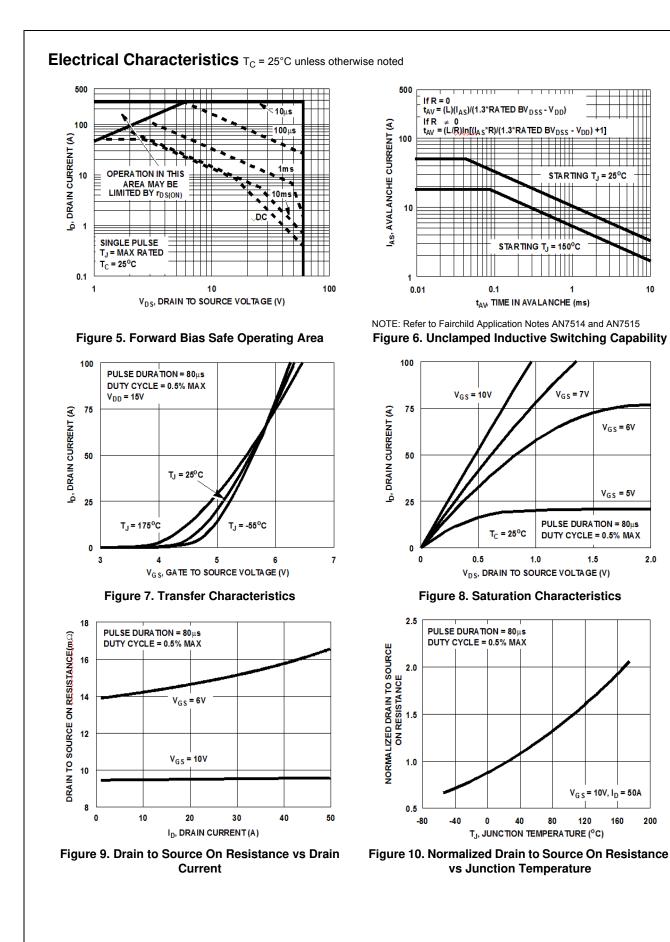
FDD10AN06A0

10

V_{G S} = 6V

V_{G S} = 5V

2.0



200

160

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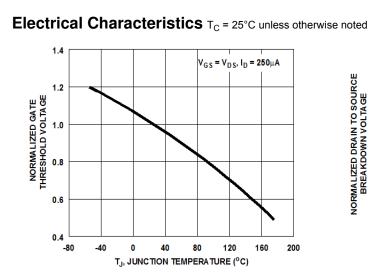


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

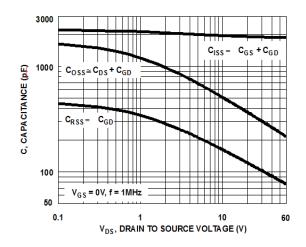


Figure 13. Capacitance vs Drain to Source Voltage

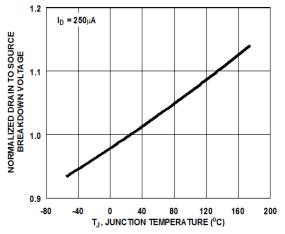


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

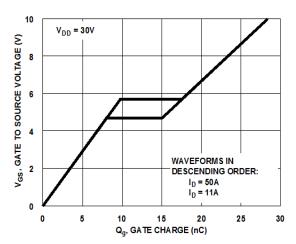


Figure 14. Gate Charge Waveforms for Constant Gate Currents

Test Circuits and Waveforms

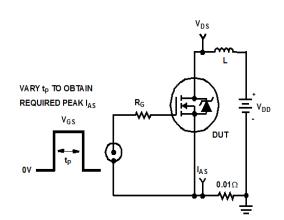


Figure 15. Unclamped Energy Test Circuit

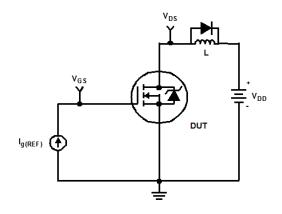


Figure 17. Gate Charge Test Circuit

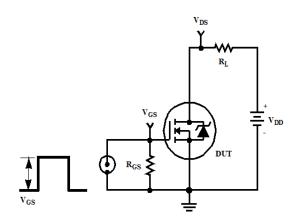


Figure 19. Switching Time Test Circuit

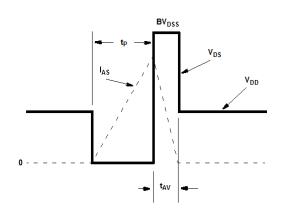
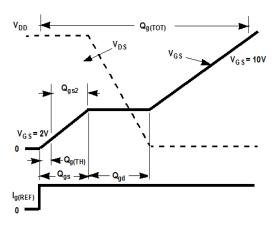


Figure 16. Unclamped Energy Waveforms





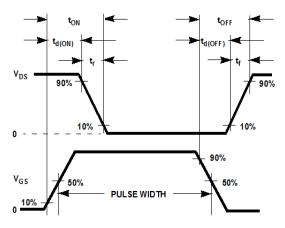


Figure 20. Switching Time Waveforms

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(EQ. 3)

Area in Centimeters Squared

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

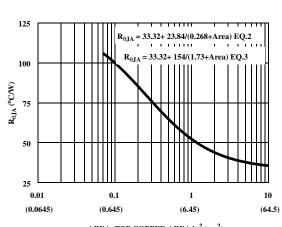
- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the R_{0JA} for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared



 $R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$



FDD10AN06A0

LDRAIN

ന്ന

RLDRAIN

DBODY

LSOURCE

ന്ന

RESOURCE

18

19

₹RVTEMP

VBAT

DRAIN

SOURCE

0

-0 2

DPLCAP

EVTHRES

 $\frac{19}{8}$

₹RSLC1

51

50

16

8

MMED

 $\left(\frac{5}{51}\right)$ ESLC

MSTRO

CIN

15

CB

EDS

14

DBREAK

EBREAK

MWEAK

RSOURCE

17

ТТ (♠

RBREAK

RVTHRES

•

11

17 18

-11

RSLC2

10

6 8

ESG

EVTEMP

 $\frac{18}{22}$

<u>13</u> 8

SIB

<u>14</u> 13

EGS $\left(\frac{6}{6}\right)$

QS2B

20

RGATE

CA

9

LGATE

RLGATE

GATE

PSPICE Electrical Model

.SUBCKT FDD10AN06A0 2 1 3 ; rev July 2002 Ca 12 8 7e-10 Cb 15 14 7e-10 Cin 6 8 1.8e-9

Dbody 7 5 DbodyMOD Dbreak 5 11 DbreakMOD Dplcap 10 5 DplcapMOD

Ebreak 11 7 17 18 67.2 Eds 14 8 5 8 1 Egs 13 8 6 8 1 Esg 6 10 6 8 1 Evthres 6 21 19 8 1 Evtemp 20 6 18 22 1

lt 8 17 1

Lgate 1 9 3.2e-9 Ldrain 2 5 1.0e-9 Lsource 3 7 1.2e-9

RLgate 1 9 32 RLdrain 2 5 10 RLsource 3 7 12

Mmed 16 6 8 8 MmedMOD Mstro 16 6 8 8 MstroMOD Mweak 16 21 8 8 MweakMOD

Rbreak 17 18 RbreakMOD 1 Rdrain 50 16 RdrainMOD 1.35e-3 Rgate 9 20 3.6 RSLC1 5 51 RSLCMOD 1e-6 RSLC2 5 50 1e3 Rsource 8 7 RsourceMOD 6e-3 Rvthres 22 8 RvthresMOD 1 Rvtemp 18 19 RvtempMOD 1 S1a 6 12 13 8 S1AMOD S1b 13 12 13 8 S1BMOD S2a 6 15 14 13 S2AMOD S2b 13 15 14 13 S2BMOD

Vbat 22 19 DC 1 ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*250),7))}

.MODEL DbodyMOD D (IS=2E-11 N=1.06 RS=3.3e-3 TRS1=2.4e-3 TRS2=1.1e-6 + CJO=1.25e-9 M=5.3e-1 TT=4.2e-8 XTI=3.9) .MODEL DbreakMOD D (RS=2.7e-1 TRS1=1e-3 TRS2=-8.9e-6) .MODEL DplcapMOD D (CJO=4.7e-10 IS=1e-30 N=10 M=0.44)

.MODEL MmedMOD NMOS (VTO=3.5 KP=5.5 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=3.6) .MODEL MstroMOD NMOS (VTO=4.25 KP=80 IS=1e-30 N=10 TOX=1 L=1u W=1u) .MODEL MweakMOD NMOS (VTO=2.92 KP=0.03 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=36 RS=0.1)

.MODEL RbreakMOD RES (TC1=9e-4 TC2=5e-7) .MODEL RdrainMOD RES (TC1=2.5e-2 TC2=7.8e-5) .MODEL RSLCMOD RES (TC1=1e-3 TC2=3.5e-5) .MODEL RsourceMOD RES (TC1=1e-3 TC2=1e-6) .MODEL RvthresMOD RES (TC1=-5.3e-3 TC2=-1.3e-5) .MODEL RvtempMOD RES (TC1=-2.6e-3 TC2=1.3e-6)

```
.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-8 VOFF=-5)
.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-5 VOFF=-8)
.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2 VOFF=-1.5)
.MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-1.5 VOFF=-2)
.ENDS
```

Note: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.

SABER Electrical Model

REV July 2002 template FDD10AN06A0 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=2e-11,nl=1.06,rs=3.3e-3,trs1=2.4e-3,trs2=1.1e-6,cjo=1.25e-9,m=5.3e-1,tt=4.2e-8,xti=3.9) dp..model dbreakmod = (rs=2.7e-1,trs1=1e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=4.7e-10,isl=10e-30,nl=10,m=0.44) m..model mmedmod = (type=_n,vto=3.5,kp=5.5,is=1e-30, tox=1) m.:model mstrongmod = (type=_n,vto=4.25,kp=80,is=1e-30, tox=1) m.:model mweakmod = (type=_n,vto=2.92,kp=80,is=1e-30, tox=1) sw_vcsp.:model s1amod = (ron=1e-5,roff=0.1,von=-8,voff=-5) LDRAIN DPLCAP DRAIN ന്ന sw vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-5,voff=-8) 02 ~~~ 10 sw vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2,voff=-1.5) RLDRAIN RSLC1 sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-1.5,voff=-2) c.ca n12 n8 = 7e-10RSLC2 ₹ c.cb n15 n14 = 7e-10 Ŧ ISCL c.cin n6 n8 = 1.8e-9 DBREAK 50 dp.dbodv n7 n5 = model=dbodvmod RDRAIN 8 ESG 11 dp.dbreak n5 n11 = model=dbreakmod DBODY EVTHRES dp.dplcap n10 n5 = model=dplcapmod (<u>19</u> 8 MWEAK LGATE EVTEM spe.ebreak n11 n7 n17 n18 = 67.2 GATE **▲**MMED $\frac{18}{22}$ EBREAK spe.eds n14 n8 n5 n8 = 1 ~~~ 20 MSTR spe.egs n13 n8 n6 n8 = 1 RLGATE ľ LSOURCE spe.esg n6 n10 n6 n8 = 1 CIN SOURCE m spe.evthres n6 n21 n19 n8 = 1 spe.evtemp n20 n6 n18 n22 = 1 \mathbf{w} RSOURCE RLSOURCE i.it n8 n17 = 1 RBREAK <u>14</u> 13 17 w 18 I.lgate n1 n9 = 3.2e-9 RVTEMP I.Idrain n2 n5 = 1.0e-9 o S2B I.Isource n3 n7 = 1.2e-9 СВ 19 CA т 14 VBAT res.rlgate n1 n9 = 32 EGS EDS res.rldrain n2 n5 = 10 res.rlsource n3 n7 = 12 RVTHRES m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod, l=1u, w=1u res.rbreak n17 n18 = 1, tc1=9e-4,tc2=5e-7 res.rdrain n50 n16 = 1.35e-3, tc1=2.5e-2,tc2=7.8e-5 res.rgate n9 n20 = 3.6 res.rslc1 n5 n51 = 1e-6, tc1=1e-3,tc2=3.5e-5 res.rslc2 n5 n50 = 1e3 res.rsource n8 n7 = 6e-3, tc1=1e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-5.3e-3,tc2=-1.3e-5 res.rvtemp n18 n19 = 1, tc1=-2.6e-3,tc2=1.3e-6 sw vcsp.s1a n6 n12 n13 n8 = model=s1amod sw vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw vcsp.s2a n6 n15 n14 n13 = model=s2amod sw vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { i (n51->n50) +=iscl iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/250))** 7)) }

FDD10AN06A0

SPICE Thermal Model

REV 23 July 2002 FDD10AN06A0T

CTHERM1 TH 6 3.2e-3 CTHERM2 6 5 3.3e-3 CTHERM3 5 4 3.4e-3 CTHERM4 4 3 3.5e-3 CTHERM5 3 2 6.4e-3 CTHERM6 2 TL 1.9e-2

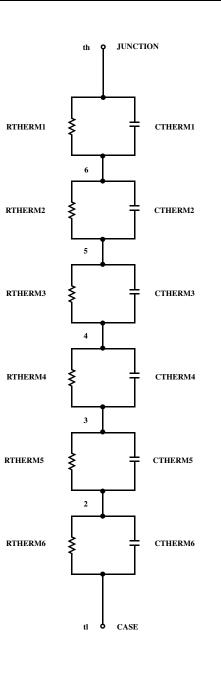
RTHERM1 TH 6 5.5e-4 RTHERM2 6 5 5.0e-3 RTHERM3 5 4 4.5e-2 RTHERM4 4 3 1.5e-1 RTHERM5 3 2 3.37e-1 RTHERM6 2 TL 3.5e-1

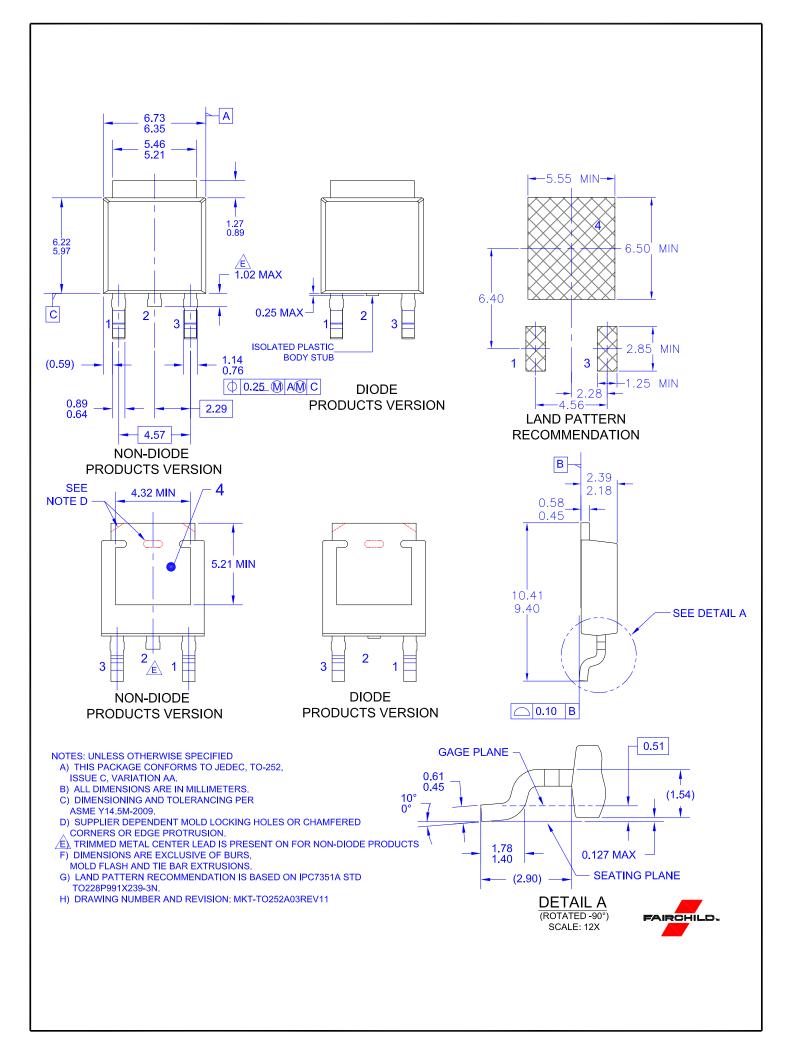
SABER Thermal Model

SABER thermal model FDD10AN06A0T template thermal_model th tl thermal_c th, tl { ctherm.ctherm1 th 6 =3.2e-3 ctherm.ctherm2 6 5 =3.3e-3 ctherm.ctherm3 5 4 =3.4e-3

ctherm.ctherm4 4 3 =3.5e-3 ctherm.ctherm5 3 2 =6.4e-3 ctherm.ctherm6 2 tl =1.9e-2

rtherm.rtherm1 th 6 =5.5e-4 rtherm.rtherm2 6 5 =5.0e-3 rtherm.rtherm3 5 4 =4.5e-2 rtherm.rtherm4 4 3 =1.5e-1 rtherm.rtherm5 3 2 =3.37e-1 rtherm.rtherm6 2 tl =3.5e-1 }





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